

**Search Notes**

Application/Control No.

10/044,325

Examiner

Ricardo Pizarro

Applicant(s)/Patent under  
Reexamination

IYER ET AL.

Art Unit

2661

**SEARCHED**

Class	Subclass	Date	Examiner
370	395.1	10/5	M
	401		
	386		
	387		
	388		
	389		
	254		
	255	10/5	M
	395.33		
	396		
	351		
	350		
	352		
	353		
	354		

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST	10/3	M
EAST	10/5	M
EAST	10/6	M

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner